



Silicon FS Trench IGBT



CRG30T65R05SDZ

General Description:

Using micro trench design and advanced Field Stop (FS) technology, offering superior conduction and switching performances.

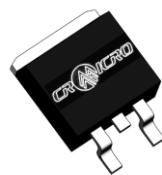
RoHS Compliant.

V_{CES}	650	V
I_C	30	A
P_{tot} (T_C=25°C)	170	W
V_{CE(sat)}	1.5	V

Features:

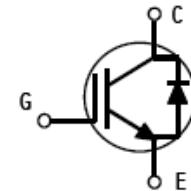
- FS Trench Technology, Positive temperature coefficient
- Low saturation voltage:
 $V_{CE(sat)}$, TYP=1.5V @ I_C =30A, V_{GE} =15V;
- Low switching loss:

TO-263



Applications

- UPS
- Solar converts
- Charger
- Motor Control



Package Parameters

Type	Package	Marking	Packing
CRG30T65R05SDZ	TO-263	G30T65R05SDZ	Tape & Reel

**Absolute Maximum Ratings** ($T_C = 25^\circ\text{C}$ unless otherwise specified):

Symbol	Parameter	Rating	Units
V_{CES}	Collector-Emitter Voltage	650	V
V_{GES}	Gate- Emitter Voltage	± 20	V
	Gate- Emitter Voltage ($t_p \leq 10\text{us}, D < 0.01$)	± 30	
I_C^{a1}	Collector Current @ $T_C = 25^\circ\text{C}$	60	A
	Collector Current @ $T_C = 100^\circ\text{C}$	30	
I_{CM}	Pulsed Collector Current @ $T_C = 25^\circ\text{C}$	120	A
I_F^{a2}	Diode Continuous Forward Current @ $T_C = 25^\circ\text{C}$	60	A
	Diode Continuous Forward Current @ $T_C = 100^\circ\text{C}$	30	
I_{FM}	Diode Maximum Forward Current	120	A
T_{sc}	Short Circuit Withstand Time @ $V_{GE}=15\text{V}, V_{CE}=400\text{V}$	6	μs
P_D	Power Dissipation @ $T_C = 25^\circ\text{C}$	170	W
	Power Dissipation @ $T_C = 100^\circ\text{C}$	85	
T_J^{a3}	Operating Junction temperature range	-40~175	$^\circ\text{C}$
T_{stg}	Storage Temperature Range	-55~150	$^\circ\text{C}$
T_L	Maximum Temperature for Soldering	270	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction to case for IGBT	--	0.88	$^\circ\text{C}/\text{W}$
$R_{\theta JC}$	Thermal Resistance, Junction to case for Diode	--	2.3	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	--	62.5	$^\circ\text{C}/\text{W}$

Electrical Characteristics of the IGBT ($T_C = 25^\circ\text{C}$ unless otherwise specified):

Symbol	Parameter	Test Conditions	SPEC			Units
			Min.	Typ.	Max.	
OFF Characteristics						
$V_{(BR)CES}$	Collector-Emitter Breakdown Voltage	$V_{GE}=0\text{V}, I_{CE}=250\mu\text{A}$	650	--	--	V
I_{CES}	Collector-Emitter Leakage Current	$V_{GE}=0\text{V}, V_{CE}=650\text{V}$	--	--	1	mA
$I_{GES(F)}$	Gate to Emitter Forward Leakage	$V_{GE}=+20\text{V}$	--	--	+250	nA
$I_{GES(R)}$	Gate to Source Reverse Leakage	$V_{GE}=-20\text{V}$	--	--	-250	nA
ON Characteristics						
$V_{CE(\text{sat})}$	Collector-Emitter Saturation Voltage	$I_C=30\text{A}, V_{GE}=15\text{V}, T_C=25^\circ\text{C}$	--	1.5	1.9	V
		$I_C=30\text{A}, V_{GE}=15\text{V}, T_C=150^\circ\text{C}$	--	1.87	--	V
$V_{GE(\text{th})}$	Gate Threshold Voltage	$I_C=250\mu\text{A}, V_{CE}=V_{GE}$	4	--	7	V

Pulse width $t_p \leq 300\mu s, \delta \leq 2\%$ **Dynamic Characteristics**

C_{ies}	Input Capacitance	$V_{CE}=30V, V_{GE}=0V$ $f=1MHz$	--	2340	--	pF
C_{oes}	Output Capacitance		--	80	--	
C_{res}	Reverse Transfer Capacitance		--	12	--	

Switching Characteristics

$t_{d(on)}$	Turn-on Delay Time	$V_{CE}=400V, I_C=30A,$ $R_g=10\Omega, V_{GE}=15V,$ Inductive Load, $T_J=25^\circ C$	--	37	--	ns
t_r	Rise Time		--	37	--	
$t_{d(off)}$	Turn-Off Delay Time		--	70	--	
t_f	Fall Time		--	69	--	
E_{on}^{a4}	Turn-On Switching Loss		--	0.68	--	mJ
E_{off}	Turn-Off Switching Loss		--	0.35	--	
E_{ts}	Total Switching Loss		--	1.03	--	
$t_{d(on)}$	Turn-on Delay Time	$V_{CE}=400V, I_C=30A,$ $R_g=10\Omega, V_{GE}=15V,$ Inductive Load, $T_J=150^\circ C$	--	37	--	ns
t_r	Rise Time		--	42	--	
$t_{d(off)}$	Turn-Off Delay Time		--	72	--	
t_f	Fall Time		--	98	--	
E_{on}^{a4}	Turn-On Switching Loss		--	0.74	--	mJ
E_{off}	Turn-Off Switching Loss		--	0.44	--	
E_{ts}	Total Switching Loss		--	1.18	--	
Q_g	Total Gate Charge	$V_{CE}=520V, I_C=30A,$ $V_{GE}=15V$	--	79	--	nC
Q_{ge}	Gate to Emitter Charge		--	21	--	
Q_{gc}	Gate to Collector Charge		--	34	--	

Electrical Characteristics of the DIODE ($T_c = 25^\circ C$ unless otherwise specified):

V_F	Diode Forward Voltage	$I_F=30A, T_c=25^\circ C$	--	1.95	2.8	V
		$I_F=30A, T_c=150^\circ C$	--	1.7	--	V
T_{rr}	Reverse Recovery Time	$I_F=30A$ $di/dt=200A/\mu s$ $T_c=25^\circ C$	--	32	--	ns
			--	3.85	--	A
			--	62	--	nC

Notes:

- a1: The collector DC current is limited by the maximum junction temperature, limited by the bond wire current capacity at $25^\circ C$
 a2: FRD DC forward current is limited by the maximum junction temperature, limited by the bond wire current capacity at $25^\circ C$
 a3: Repetitive rating; pulse width limited by maximum junction temperature $T_{vjop} = 175^\circ C$, the maximum duty cycle is less than 20% (lasting for 60s at most)
 a4: Turn-on losses include diode losses

Typical Performance Characteristics:

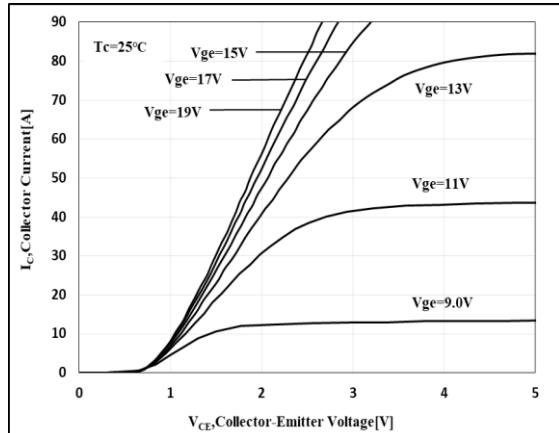


Figure 1.Output Characteristics

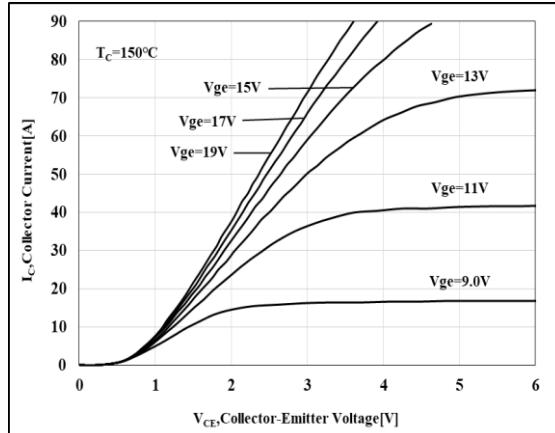


Figure 2.Output Characteristics

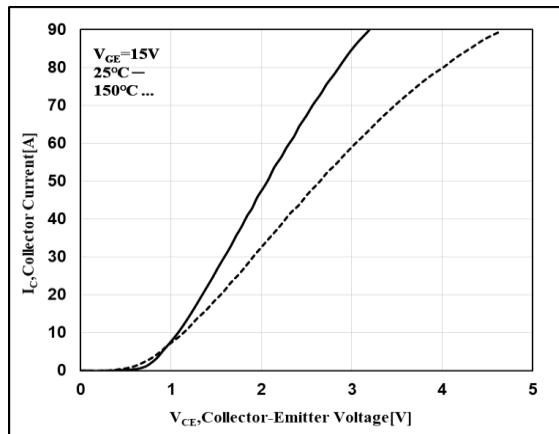


Figure 3.Saturation Voltage Characteristics

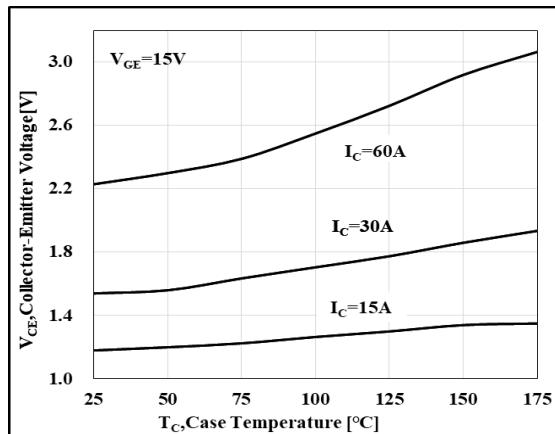


Figure 4.Saturation Voltage - T_c Characteristics

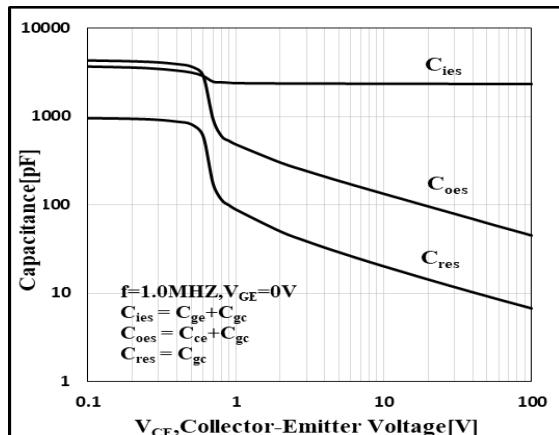


Figure 5.Capacitance Characteristics

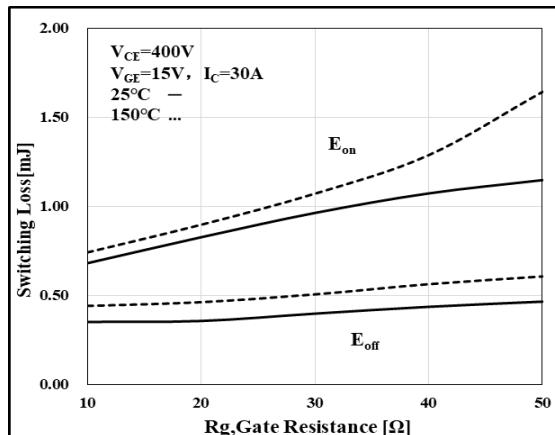
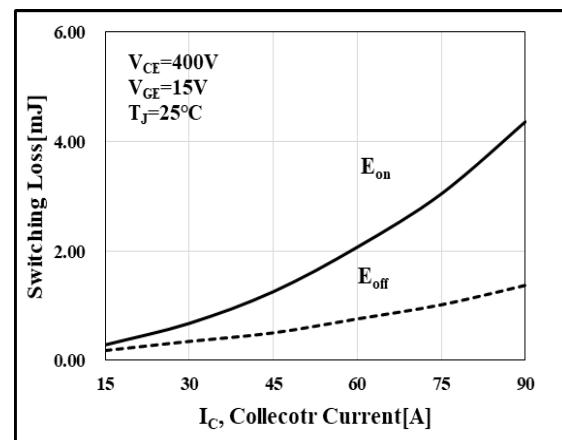
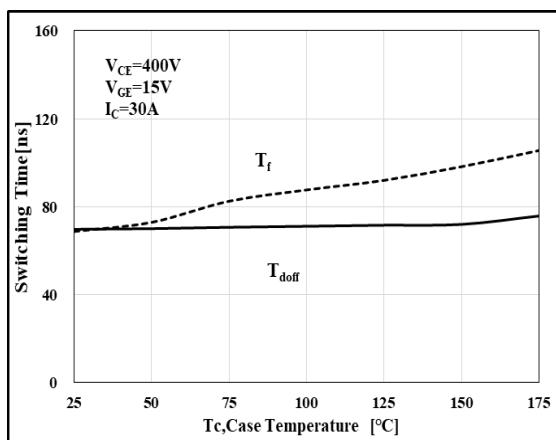
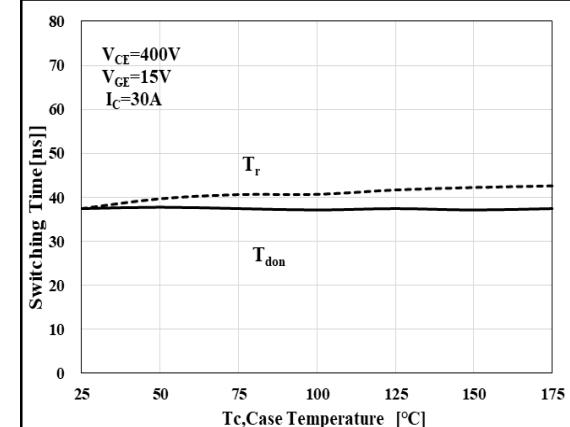
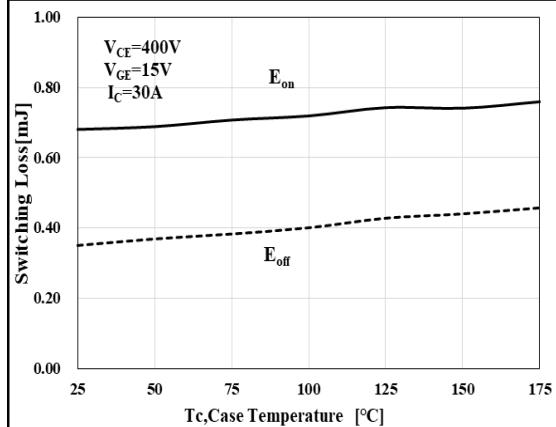
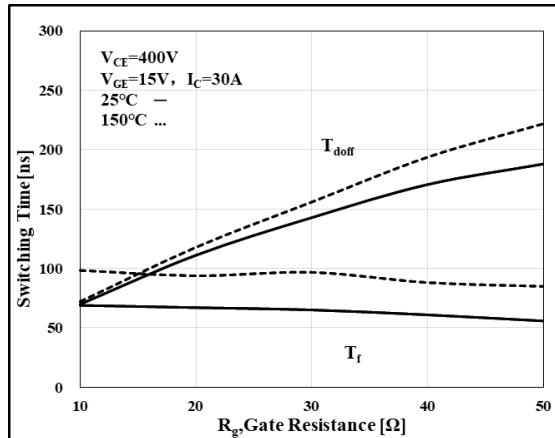
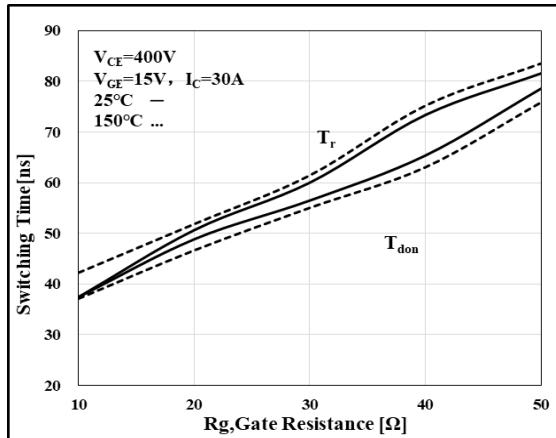


Figure 6.Switching Loss- R_g Characteristics



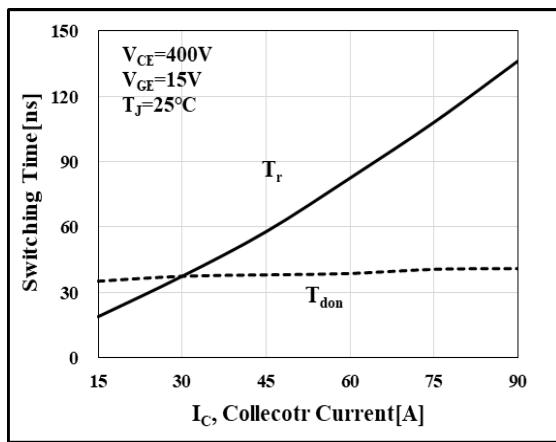


Figure 13.Switching Time-Ic Characteristics

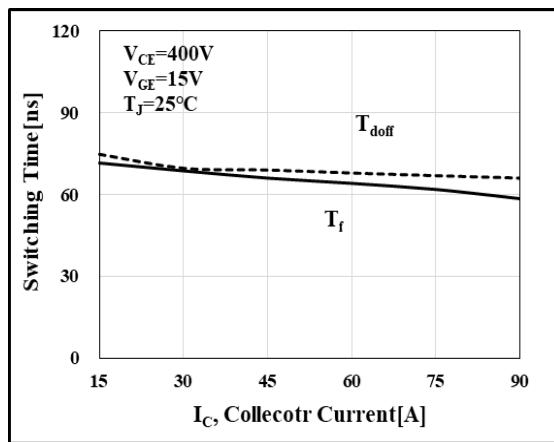


Figure 14.Switching Time-Ic Characteristics

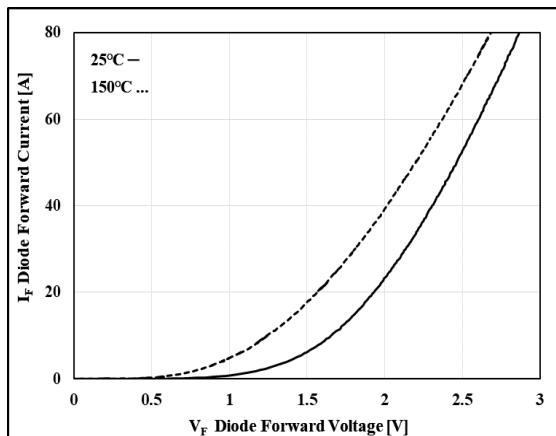


Figure 15.Diode Forward Characteristics

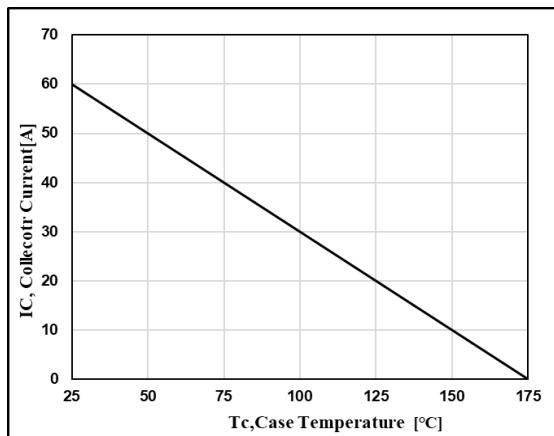


Figure 16.Collector Current-Tc Characteristics

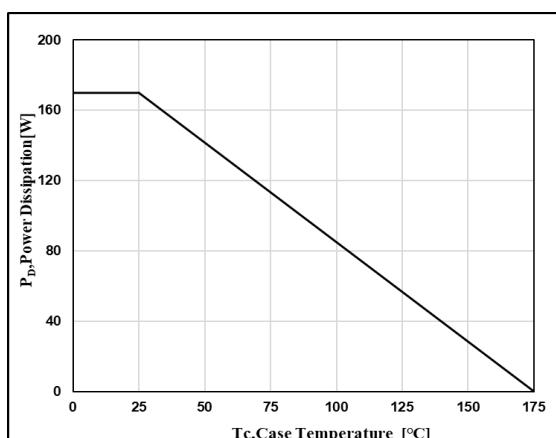


Figure 17.Power dissipation

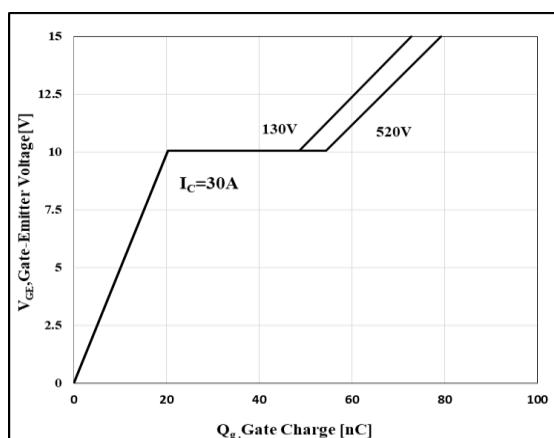


Figure 18.Gate Charge Characteristics

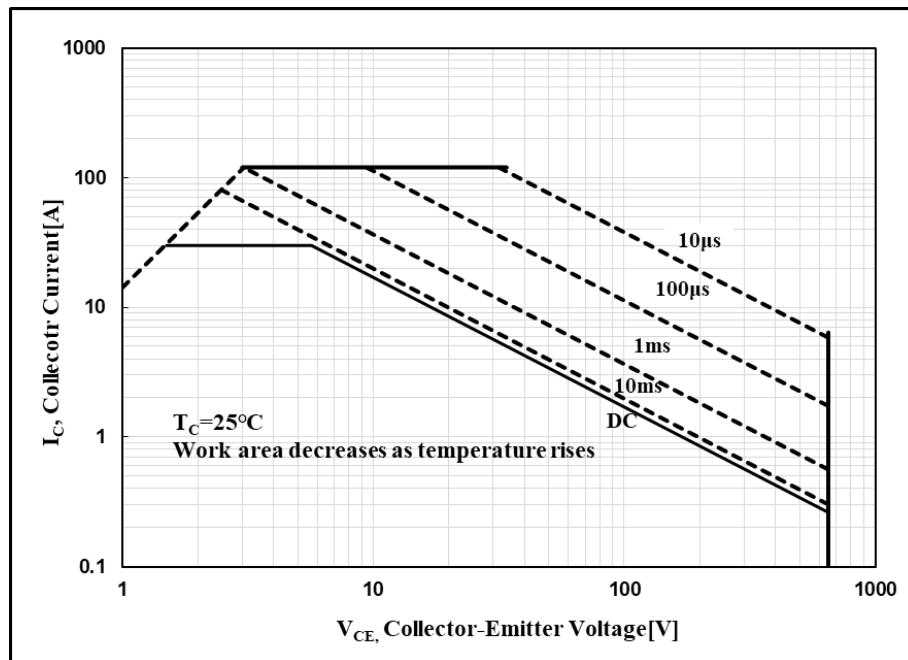


Figure 19.Forward Bias Safe Operating Area

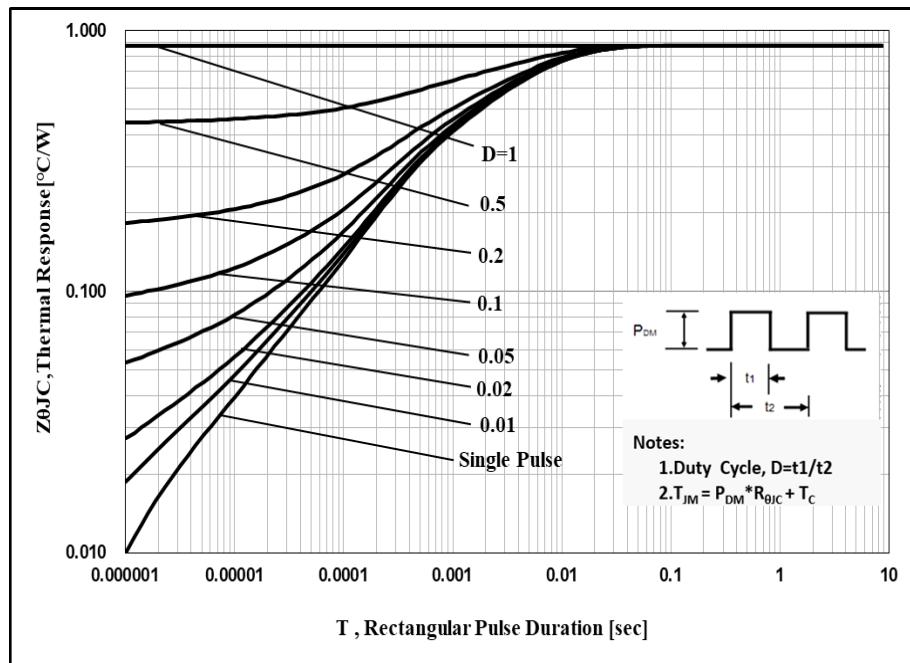
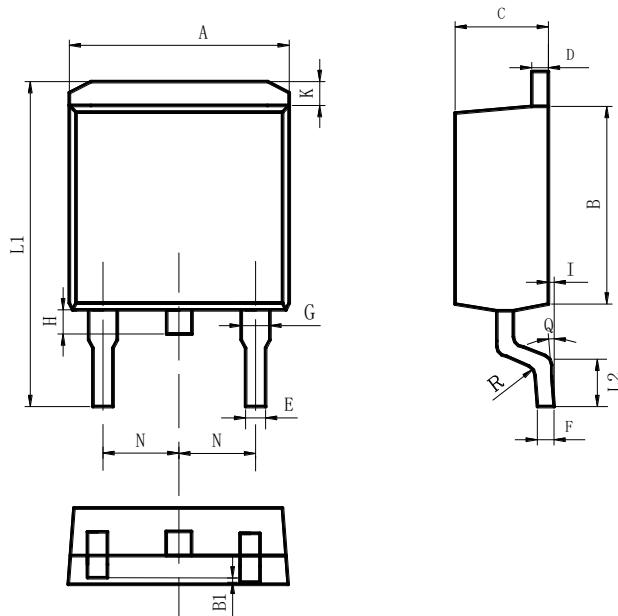


Figure 20.IGBT Transient Thermal Impedance

Package Information



Items	Values(mm)	
	MIN	MAX
A	9.80	10.40
B	8.90	9.50
B1	0	0.10
C	4.40	4.80
D	1.16	1.37
E	0.70	0.95
F	0.30	0.60
G	1.07	1.47
H	1.30	1.80
K	0.97	1.37
L1	14.50	16.50
L2	1.60	2.30
I	0	0.2
Q	0°	8°
R	0.4	
N	2.39	2.69

TO-263 Package



The name and content of poisonous and harmful material in products

Warnings

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. It is suggested to be used under 80 percent of the maximum ratings of the device.
 2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
 3. IGBTs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
 4. This publication is made by Huajing Microelectronics and subject to regular change without notice.

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CRG30T65R05SDZ



Modify :

Version	Modify record
2024V01	Initial release